
HEWLETT-PACKARD JOURNAL INDEX

Volume 44 January 1993 through December 1993

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Part 1: Chronological Index

February 1993

Photonic Technology for Lightwave Communications Test Applications, *Waguil S. Ishak, Kent W. Carey, Steven A. Newton, and William R. Trutna, Jr.*

Tunable Laser Sources for Optical Amplifier Testing, *Bernd Maisenbacher, Edgar Leckel, Robert Jahn, and Michael Pott*

External-Cavity Laser Design and Wavelength Calibration, *Emmerich Müller, Wolfgang Reichert, Clemens Rück, and Rolf Steiner*

External-Cavity Laser Temperature Stabilization and Power Control, *Horst Schweikardt and Edgar Leckel*

Dual-Output Laser Module for a Tunable Laser Source, *Roger L. Jungerman, David M. Braun, and Kari K. Salomaa*

Research on External-Cavity Lasers, *William R. Trutna, Jr. and Paul Zorabedian*

Design of a Precision Optical Low-Coherence Reflectometer, *D. Howard Booster, Harry Chou, Michael G. Hart, Steven J. Mifsud, and Rollin F. Rawson*

Averaging Measurements to Improve Sensitivity

Fabrication of Diffused Diodes for HP Lightwave Applications, *Patricia A. Beck*

High-Resolution and High-Sensitivity Optical Reflection Measurements Using White-Light Interferometry, *Harry Chou and Wayne V. Sorin*

A Modular All-Haul Optical Time-Domain Reflectometer for Characterizing Fiber Links, *Josef Beller and Wilfried Pless*

A High-Performance Signal Processing System for the HP 8146A Optical Time-Domain Reflectometer, *Josef Beller*

Improving SNR by Averaging

Design Considerations for the HP 8146A OTDR Receiver, *Frank Maier*

User Interface Design for the HP 8146A OTDR, *Robert Jahn and Harald Seeger*

Analyzing OTDR Traces on a PC with a Windows User Interface

High-Performance Optical Return Loss Measurement, *Siegmar Schmidt*

High-Speed Time-Domain Lightwave Detectors, *Randall King, David M. Braun, Stephen W. Hinch, and Karl Shubert*

InP/InGaAs/InP P-I-N Photodetectors for High-Speed Lightwave Detectors

Calibration of Lightwave Detectors to 50 GHz, *David J. McQuate, Kok Wai Chang, and Christopher J. Madden*

April 1993

A New Family of Microwave Signal Generators for the 1990s, *William W. Heinz, Ronald E. Pratt, and Peter H. Fisher*

Broadband Fundamental Frequency Synthesis from 2 to 20 GHz, *Brian R. Short, Thomas L. Grisell, and Edward G. Cristal*

A New High-Performance 0.01-to-20-GHz Synthesized Signal Generator Microwave Chain, *William D. Baumgartner, John S. Brenneman, John L. Imperato, Douglas A. Larson, Ricardo de Mello Peregrino, and Gregory A. Taylor*

Internal Pulse Generator

Concurrent Signal Generator Engineering and Manufacturing, *Christopher J. Bostak, Camala S. Kolseth, and Kevin G. Smith*

A Design for Manufacturability, Design for Testability Checklist

A New Generation of Microwave Sweepers, *Alan R. Bloom, Jason A. Chodora, and James R. Zellers*

Third-Order Curve-Fit Algorithm

A Digitally Corrected Fractional-N Synthesizer

Microcircuits for the HP 83750 Series Sweepers, *Eric V.V. Heyman, Rick R. James, and Roger R. Graeber*

A Programmable 3-GHz Pulse Generator, *Hans-Jürgen Wagner*
Pulse/Data Channel Extends Programmable Pulse Generator Applications, *Christoph Kalkuhl*

Design of a 3-GHz Pulse Generator, *Peter Schinzel, Andreas Pfaff, Thomas Dippon, Thomas Fischer, and Allan R. Armstrong*

Cooling of the Frequency Divider IC

A Multirate Bank of Digital Bandpass Filters for Acoustic Applications, *James W. Waite*

Continuous Monitoring of Remote Networks: The RMON MIB, *Matthew J. Burdick*

The HP 64700 Embedded Debug Environment: A New Paradigm for Embedded System Integration and Debugging, *Robert D. Gronlund, Richard A. Nygaard Jr., and John T. Rasper*

The Value of Usability

The Debug Environment Connection to HP SoftBench

A Real-Time Operating System Measurement Tool

A New Perspective on Emulation Hardware Modularity

Software Performance Analysis of Real-Time Embedded Systems, *Andrew J. Blasciak, David L. Neuder, and Arnold S. Berger*

June 1993

ORCA: Optimized Robot for Chemical Analysis, *Gary B. Gordon, Joseph C. Roark, and Arthur Schleifer*

The HP ORCA System Outside the Analytical Laboratory

Gravity-Sensing Joy Stick

Absolute Digital Encoder

HP OpenODB: An Object-Oriented Database Management System for Commercial Applications, *Rafiu Ahad and Tu-Ting Cheng*

The HP Ultra VGA Graphics Board, *Myron R. Tuttle, Kenneth M. Wilson, Samuel H. Chau, and Yong Deng*

POSIX Interface for MPE/iX, *Rajesh Lalwani*

A Process for Preventing Software Hazards, *Brian Connolly*

Configuration Management for Software Tests, *Leonard T. Schroath*

Implementing and Sustaining a Software Inspection Program in an R&D Environment, *Jean M. MacLeod*

The Use of Total Quality Control Techniques to Improve the Software Localization Process, *John W. Goodnow, Cindie A. Hammond, William A. Koppes, John J. Krieger, D. Kris Rovell-Rixx, and Sandra J. Warner*

Tools for the Language Translation Process

A Transaction Approach to Error Handling, *Bruce A. Rafnel*

Error Definition

User Interface Management System for HP-UX System Administration Applications, *Mark H. Notess*

SAM versus Manual Administration

August 1993

High-Efficiency Aluminum Indium Gallium Phosphide Light-Emitting Diodes, *Robert M. Fletcher, Chihping Kuo, Timothy D. Osentowski, Jiann Gwo Yu, and Virginia M. Robbins*

The Structure of LEDs: Homojunctions and Heterojunctions

HP Task Broker: A Tool for Distributing Computational Tasks, *Terrence P. Graf, Renato G. Assini, John M. Lewis, Edward J. Sharpe, James J. Turner, and Michael C. Ward*

HP Task Broker and Computational Clusters

Task Broker and DCE Interoperability

HP Task Broker Version 1.1

The HP-RT Real-Time Operating System, *Kevin D. Morgan*

An Overview of Threads

Managing PA-RISC Machines for Real-Time Systems, *George A. Anzinger*

Context Switching in HP-RT

Protecting Shared Data Structures

The Shadow Register Environment

C Environment

The HP Tsutsui Logic Synthesis System, *W. Bruce Culbertson, Toshiki Osame, Yoshisuke Otsuru, J. Barry Shackleford, and Motoo Tanaka*

Designing a Scanner with Color Vision, *K. Douglas Gennetten and Michael J. Steinle*

Mechanical Considerations for an Industrial Workstation, *Brad Clements*

Online CO₂ Laser Beam Real-Time Control Algorithm for Orthopedic Surgical Applications, *Franco A. Canestri*

Online Defect Management via a Client/Server Relational Database Management System, *Brian E. Hoffmann, David A. Keefer, and Douglas K. Howell*

Client/Server Database Architecture

Realizing Productivity Gains with C++, *Timothy C. O'Konski*

Glossary

Bridging the Gap between Structured Analysis and Structured Design for Real-Time Systems, *Joseph M. Luszcz and Daniel G. Maier*

Structured Analysis and Structured Design Refresher

October 1993

An 8-Gigasample-per-Second Modular Digitizing Oscilloscope System, *John A. Scharrer*

An 8-Gigasample-per-Second, 8-Bit Data Acquisition System for a Sampling Digital Oscilloscope, *Michael T. McTigue and Patrick J. Byrne*

A Digitizing Oscilloscope Time Base and Trigger System Optimized for Throughput and Low Jitter, *David D. Eskeldson, Reginald Kellum, and Donald A. Whiteman*

A Rugged 2.5-GHz Active Oscilloscope Probe, *Thomas F. Uhling and John R. Sterner*

Accuracy in Interleaved ADC Systems, *Allen Montijo and Kenneth Rush*

Dither and Bits

Filter Design for Interpolation

A Study of Pulse Parameter Accuracy in Real-Time Digitizing Oscilloscope Measurements, *Kenneth Rush*

Architectural Design for a Modular Oscilloscope System, *Dana L. Johnson and Christopher J. Magnuson*

A Survey of Processes Used in the Development of Firmware for a Multiprocessor Embedded System, *David W. Long and Christopher P. Duff*

Developing Extensible Firmware

Mechanical Design of a New Oscilloscope Mainframe for Optimum Performance, *John W. Campbell, Kenneth W. Johnson, Wayne F. Helgoth, and William H. Escovitz*

A Probe Fixture for Wafer Testing High-Performance Data Acquisition Integrated Circuits, *Daniel T. Hamling*

A High-Performance 1.8-GHz Vector Network and Spectrum Analyzer, *Shigeru Kawabata and Akira Nukiyama*

Receiver Design for a Combined RF Network and Spectrum Analyzer, *Yoshiyuki Yanagimoto*

DSP Techniques for Digital IF

A Fast-Switching, High-Isolation Multiplexer, *Yoshiyuki Yanagimoto*

A 10-Megasample-per-Second Analog-to-Digital Converter with Filter and Memory, *Howard E. Hilton*

A 10-MHz Analog-to-Digital Converter with 110-dB Linearity, *Howard E. Hilton*

December 1993

Vector Signal Analyzers for Difficult Measurements on Time-Varying and Complex Modulated Signals, *Kenneth J. Blue, Robert T. Cutler, Dennis P. O'Brien, Douglas R. Wagner, and Benjamin R. Zarlingo*

The Resampling Process

Applications for Demodulation

A Firmware Architecture for Multiple High-Performance Measurements, *Dennis P. O'Brien*

Run-Time-Configurable Hardware Drivers

Remote Debugging

Baseband Vector Signal Analyzer Hardware Design, *Manfred Bartz, Keith A. Bayern, Joseph R. Diederichs, and David F. Kelley*

ADC Bits, Distortion, and Dynamic Range

What Is Dithering?

RF Vector Signal Analyzer Hardware Design, *Robert T. Cutler, William J. Ginder, Timothy L. Hillstrom, Kevin L. Johnson, Roy L. Mason, and James Pietsch*

Microwave Plate Assembly

A Versatile Tracking and Arbitrary Source

Vector Measurements beyond 1.8 GHz	A Two-Axis Micropositioner for Optical Fiber Alignment, <i>J. Douglas Knight and Joseph N. West</i>
Optical Spectrum Analyzers with High Dynamic Range and Excellent Input Sensitivity, <i>David A. Bailey and James R. Stimple</i>	A Standard Data Format for Instrument Data Interchange, <i>Michael L. Hall</i>
Optical Spectrum Analysis	North American Cellular CDMA, <i>David P. Whipple</i>
A Double-Pass Monochromator for Wavelength Selection in an Optical Spectrum Analyzer, <i>Kenneth R. Wildnauer and Zoltan Azary</i>	Cellular Technologies
Diffraction Grating	DECT Measurements with a Microwave Spectrum Analyzer, <i>Mark A. Elo</i>
Polarization Sensitivity	
A High-Resolution Direct-Drive Diffraction Grating Rotation System, <i>Joseph N. West and J. Douglas Knight</i>	

Part 2: Subject Index

Subject	Page/Month
A	
Abstract data types	85/Aug.
Access control definition	45/June
Access control, HP OpenODB	28/June
Accuracy, oscilloscope	8, 38, 47/Oct.
Acoustics, industrial workstation	65/Aug.
Acquisition system, oscilloscope	9, 11, 13/Oct.
Active measurement mode	23/Dec.
Active probe	31/Oct.
Activity measurements	108/Apr.
ADARTS (Ada-based Design Approach to Real-Time Systems)	90/Aug.
ADC, 10-MSa/s	100/Oct.
ADC bits, distortion, dynamic range	38/Dec.
ADC chips	14/Oct.
ADC, large-scale dithered	36/Dec.
ADC system, 8-GSa/s	13/Oct.
Address alignment	111/Apr.
Affinity value	17/Aug.
Agent, RMON	85/Apr.
Aggregate object	24/June
Airflow management, industrial workstation	65/Aug.
Algorithm, laser surgery	68/Aug.
Algorithm, third-order curve fit	41/Apr.
AlInGaN LEDs	6/Aug.
All-haul optical time-domain reflectometry	60/Febr.
Amplifier, output	24, 65/Apr., 36/Dec.
Amplifier, shaping	63/Apr.
Amplifier, switchable gain	35/Dec.
Amplifier, transimpedance	42/Febr., 71/Dec.
Amplifier, traveling-wave	22/Apr.
Amplitude modulation	25/Apr.
Analytical robot	6/June
Analyzer, real-time frequency	73/Apr.
Analyzer, software performance	98, 107/Apr.
Analyzers, vector signal	6/Dec.
Anti-alias filtering	41, 101/Oct., 36/Dec.
Antireflection coating	20, 32/Febr.
Aperture wheel	69, 76/Dec.
Application development, robot	13/June
Arbitration, multiprocess	95/Apr.
Architecture, multiprocess	94/Apr.
Architecture, oscilloscope	51/Oct.
ASIC design system	38/Aug.
Assault handling	27/Dec.
Atomic object	24/June
Attenuator, optical	14/Febr.
Attenuators	34, 49/Dec.
Attenuators, FET	22/Apr.
Baseband vector analyzer	31/Dec.
Batch	31/Aug.
Bipolar sampler	17/Oct.
Bistability	36/Febr.
Block diagram design entry	43/Aug.
Bone characteristics	68/Aug.
Bricks	66/Aug.
Bright LEDs	6/Aug.
Burst timing, DECT	102/Dec.
C	
C++	85/Aug.
C/C++ debugger	93/Apr.
C environment	35/Aug.
Calibration, ADC	39/Oct.
Calibration, ADC residue gain	109/Oct.
Calibration, DAC	109/Oct.
Calibration, lightwave detectors	87/Febr.
Calibration, pulse generator	69/Apr.
Calibration, tunable laser	25, 30/Febr.
Calibration, vector signal analyzer	54/Dec.
Call stack	111/Apr.
Callee-saves	
and caller-saves registers	36/Aug.
Carrier frequency determination	13/Dec.
CCD detector	53, 55/Aug.
CDMA, North American cellular	90/Dec.
Cellular CDMA system	90/Dec.
Cellular technologies	92/Dec.
Ceramic substrate breakage	34/Oct.
CGA	31/June
Chief moderator	61/June
Chromatic dispersion	56/Febr.
Client/server architecture	77/Aug.
Client/server database architecture	22/June, 78/Aug.
Clocks, oscilloscope	29/Oct.
Coating, antireflection	20, 32/Febr.
Collective computing	15, 16/Aug.
Color Graphics Adapter	31/June
Color matching	54/Aug.
Color science	52/Aug.
Color separation, scanner	54, 55/Aug.
Complex objects	20/June
Component interface specifications	95/Aug.
Component versions	54/June
Computational clusters	16/Aug.

Computed function 27/June
 Concrete data types 85/Aug.
 Configuration file,
 HP Task Broker 16/Aug.
 Configuration management 53/June
 Connectivity, industrial
 workstation 63/Aug.
 Contact strip,
 oscilloscope cabinet 68/Oct.
 Context independent
 error codes 72/June
 Context switching 32/Aug.
 Control, measurement 23/Dec.
 Converter, analog-to-digital see ADC
 Cooling, IC 61/Apr.
 Correction of time data 10/Dec.
 Correlator, ADC 39/Dec.
 Cost of a variable 46/Aug.
 Counter circuit, UHF 52/Dec.
 Coupler, leveling 20/Apr.
 Coupling, low-noise 26/Oct.
 Curve-fit algorithm 41/Apr.
 Customization,
 measurement 22, 26/Dec.
 Cyanate ester 48/Dec.

D

Daemon, emulation system 95/Apr.
 Data interchange format 85/Dec.
 Data narrowing 87/Aug.
 Data vector architecture 18/Dec.
 Data viewer 47/Aug.
 Database, object-oriented 20/June
 DCE interoperability 19/Aug.
 Debug environment,
 embedded system 90/Apr.
 Debugger macros 105/Apr.
 Debugging, remote 29/Dec.
 Decimation, HP 8146A 64/Feb.
 Decimation filtering 102/Oct., 41/Dec.
 Decimation, sample rate 76/Apr.
 DECT 98/Dec.
 Defect causes 62/June
 Defect management system
 (DMS) 73/Aug.
 Defect prevention 63/June
 Defect sharing 77/Aug.
 Defect tracking system 74/Aug.
 Delay loop 58/Apr.
 Delay, switched 62/Apr.
 Delay, variable 62/Apr.
 Demodulation, AM, FM, PM 11, 12/Dec.
 Demodulation, DECT 103/Dec.
 Derived function 27/June
 Design for manufacturability 30/Apr.

Detectors, lightwave 83/Feb.
 Development environment,
 HP-RT 24/Aug.
 Diffraction grating 12, 20/Febr., 70/Dec.
 Diffraction grating rotator 77/Dec.
 Diffused diodes 49/Febr.
 Diffusion barrier 50/Febr.
 Digital signal
 processing 40, 74/Apr., 8, 73/Dec.
 Digitizing oscilloscopes 6/Oct.
 Dim and burst signaling 93/Dec.
 Direct-drive diffraction grating
 system 75/Dec.
 Directory structure, MPE/iX 41/June
 Display driver, HP Ultra VGA 32, 38/June
 Distortion, ADC 106, 107/Oct.
 Distributed feedback lasers 66/Dec.
 Dither, ADC 41, 42, 44/Oct.
 Dithering, large-scale 36, 44/Dec.
 Dividers,
 binary frequency 18, 24, 58/Apr.
 Double-balanced mixer 86/Oct.
 Double-pass monochromator 68/Dec.
 Down-converter, vector analyzer 58/Dec.
 Drivers, run-time-configurable 20/Dec.
 DSP techniques 90/Oct.
 Dual YIG oscillator 46/Apr.
 Duration measurements 109/Apr.
 Duroid 17, 19/Apr.
 Dynamic typing 21/June

E

EDFAs 11/Febr.
 EGA 31/June
 Embedded system debugging 90/Apr.
 EMC design 70/Apr.
 Emissions due to modulation 101/Dec.
 Emulator/analyizer 92/Apr.
 Encoder, absolute digital 14/June
 Enhanced Graphics Adapter 31/June
 Ergonomics, HP Ultra VGA 36/June
 Error definition 72/June
 Error handling 71/June
 Errors, time base 24/Oct.
 Etalon 13, 21/Febr.
 ETSI 98/Dec.
 Event tree analysis 50/June
 Exceptions 88/Aug.
 External-cavity
 lasers 7, 11, 20, 28, 32, 35/Febr.
 External function 27/June

F

Fabry-Perot lasers 65/Dec.

Failure modes
 and effects analysis 49/June
 Fault tree analysis 49/June
 FFT in analyzers 8/Dec.
 Field solver program 19/Apr.
 File access and control, MPE/iX 44/June
 File naming, MPE/iX 43/June
 Filter, anti-aliasing 41, 101/Oct., 36/Dec.
 Filter, bandwidth limit 44/Oct.
 Filter, IF 19/Oct.
 Filter, interpolation 45/Oct.
 Filtering, zoom and decimation 102/Oct.
 Filters, decimation 41/Dec.
 Filters, harmonic 25/Apr.
 Filters, low-pass switched 23/Apr.
 Filters, multirate digital 73/Apr.
 Finesse 23/Febr.
 Firmware development,
 oscilloscope 59, 64/Oct.
 Firmware, optical source 15/Febr.
 Firmware, signal generator 10/Apr.
 Firmware, vector signal analyzer 17/Dec.
 Fishbone diagram 66/June
 FISO memory 14/Oct.
 Flash ADC 14/Oct.
 Flexure plate 81/Dec.
 Flow graph optimization 78/Apr.
 Form factor 65/Aug.
 Forward link encoding 94/Dec.
 Fractional-N
 phase-locked loop 14, 42, 44/Apr.
 Free spectral range 23/Febr.
 Frequency control 39/Apr.
 Frequency conversion 49, 50, 51/Dec.
 Frequency diversity 92/Dec.
 Frequency measurement 63/Apr.
 Frequency modulation 13/Apr.
 Frequency selective analysis 9/Dec.
 Frequency synthesis,
 broadband fundamental 12, 38/Apr.
 Frequency synthesis
 subsystem 12, 42/Apr.
 Full width at half maximum
 (FWHM) 54/Febr., 64/Dec.
 Function duration
 measurements 110/Apr.
 Functions, HP OpenODB 26/June

G

Gate array, data 57/Apr.
 Gear backlash 77/Dec.
 Ghost elimination 75/Febr.
 Graphics engine, HP Ultra VGA 32/June

Grating, diffraction 12, 20/Feb., 68, 70 Dec.
Gravity-sensing joy stick 12/June

H

Handle classes, C++ 87/Aug.
Hard floor 38, 40/Dec.
Harmonic drive reduction 11/June
Hazard avoidance process 48/June
Hercules Graphics Card 31/June
Heterodyne band microcircuit 49/Apr.
Heterogeneity 15, 79/Aug.
Heterojunction LEDs 8/Aug.
HGC 31/June
High-isolation shielding 98/Oct.
High-speed multiplexer 95/Oct.
Homojunction LEDs 8/Aug.
HP CMOS, HP Ultra VGA 38/June
HPUVGA utility 37/June
Hybrid ADC channel 14/Oct.

I

IF detection 88/Oct.
Impulse response, photoreceiver 88/Feb.
Industrial workstation 62/Aug.
Input, analog 32/Dec.
Input sensitivity, HP 71450A/51A 62/Dec.
Input trip 34/Dec.
Integration, discrete 78/Apr.
Integrity and security, DMS 79/Aug.
Interconnect, plug-in 68/Oct.
Interface classes, C++ 86/Aug.
Interleaved ADC system 15, 38/Oct.
Interleaving (HP 8146A) 64/Feb.
Interpolation, waveform 45/Oct.
Interpolator, time base 27/Oct.
Interrupt handling 33/Aug.
Interruptability 25/Aug.
Intersymbol interference 43/Oct.
Intertask communication 94/Aug.
Interval duration measurements 109/Apr.
I/O architecture 33/Aug.
ISA bus 33/June
Isolators, optical 7/Feb.

J

Jitter, oscilloscope 25/Oct.
Joint space, robot 11/June
Joint servos 13/June
Joy stick 12/June

K

kCode 26/Dec.

Kernel semaphores 27/Aug.
Kernel software, HP-RT 24, 25/Aug.
Kinematics processor 11/June

L

Laboratory robot 6/June
Language translation 68/June
Laplacian potential solver 19/Apr.
Laser control algorithm 68/Aug.
Laser module 32/Feb.
Lasers,
external-cavity 7, 11, 20, 28, 32, 35/Feb.
Lasers, semiconductor 7/Feb.
Lasers, YAG 7/Feb.
Late binding 21/June
Lathe/robot system 9/June
Layered manufacturing 30/Apr.
LEDs 6/Aug.
Lifetime of a variable 46/Aug.
Light-emitting diodes 6/Aug., 63/Dec.
Linear actuator 82/Dec.
Linearity, ADC 105/Oct.
Linearity correction, ADC 42/Oct.
Literal object 24/June
LO feedthrough cancellation 49/Dec.
LO loop 15/Apr.
LO, vector analyzer 41, 51/Dec.
Logic synthesis system 38/Aug.
Logical Description Format 43/Aug.
Long code 94/Dec.
Low-band output section 23/Apr.
Low-coherence reflectometer 39/Feb.
Low-transient design 97/Oct.
Luminous performance, LED 12/Aug.

M

Manufacturing, signal generator 30/Apr.
Markers 111/Apr.
Maximum power curve 18/February
MDA 31/June
Measurement sequencers 21/Dec.
Mechanical design, oscilloscope 66/Oct.
Mechanical design,
pulse generator 71/Apr.
Medical information
and monitoring system 47/June
Memory chip 14/Oct.
Memory depth, oscilloscope 14, 20/Oct.
Memory leaks 87/Aug.
Mesa pi-n diodes 49/February
Message distribution 96/Apr.
Metamerism 53/Aug.
Metrics, software inspections 62/June
Methods development software 8/June

MIB 82/Apr.
Michelson interferometer 39, 53/February
Microcircuits,
hybrid 19, 21, 46, 62, 63, 65/Apr., 14/Oct.
Microwave chain 17/Apr.
Microwave plate assembly 50/Dec.
Mixer, GaAs RFIC 49/Apr.
Modulation module 21/Apr.
Modulation transfer function
(MTF) 55/Aug.
Modulator amplifier
microcircuit 50/Apr.
Modulator-based
optical test system 89/February
Modulators, optical 7/February
Module generators 39/Aug.
Monochrome Display Adapter 31/June
Mooz mode 42/Dec.
Motion, robot 14/June
MPE directory structure 41/June
MPE/iX directory structure 42/June
Multimeter, lightwave 81/February
Multimodelling 37/February
Multipath 92/Dec.
Multiple inheritance 21/June
Multiplexer 95/Oct.
Multiprocessing
operating system 72/February
Multirate digital bandpass filters 73/Apr.
Multithreaded kernel 25/Aug.

N

Native language help text 73/February
Negative delay 58/Apr.
Netlists 38/Aug.
Network analyzer 76/Oct.
Network monitoring 82/Apr.
Node classes, C++ 86/Aug.
Noise, ADC 106/Oct.
Nonlinearities, time base 25/Oct.

O

Object action manager (ObAM) 81/June
Object, HP OpenODB 24/June
Object models 23/June
Object-oriented modeling 20/June
Object-oriented
programming language 24/June
Octave-band analysis 73/Apr.
Offset loop 14/Apr.
OMVPE 8/Aug.
OOPL 24/June
OpenODB model 23/June
Optical deck 45/February

Optical frequency-domain reflectometry 52/Feb.
 Optical heterodyne test system 88/Feb.
 Optical impulse test system 87/Feb.
 Optical spectrum analysis 62/Dec.
 Optical spectrum analyzers 60/Dec.
 Optical sources, tunable 11/Feb.
 Optical time-domain reflectometry (OTDR) 52, 61/Feb.
 Optimization, filter 77, 78/Apr.
 Optimization, logic 41/Aug.
 Optoblock 13, 24/Feb.
 ORCA robot 6/June
 Orthopedic surgery laser control 68/Aug.
 Oscillator transient measurements 12/Dec.
 Oscilloscopes, 8-GSa/s 6/Oct.
 OTDR receiver 69/Feb.
 Output module 19/Apr.
 Overloaded functions 21, 28/June

P

Package structuring 94/Aug.
 Packet capture 87/Apr.
 PA-RISC machines 31, 32/Aug.
 PC video 31/June
 Peephole optimizations 41/Aug.
 Performance verification 57/Dec.
 Period generation 60/Apr.
 Phase accuracy 77/Apr.
 Phase noise 14/Apr.
 Phase noise measurements 12/Dec.
 Photodetectors 8, 49, 83, 85, 87/Feb.
 Photodiode, HP 71450A/51A 71/Dec.
 Photoluminescence 9/Feb.
 Photonic technology 6/Feb.
 Physical layer, DECT 99/Dec.
 PID servo loop 14/Feb.
 Pilot signal 94/Dec.
 P-i-n photodetectors, HP 8504A 49/Feb.
 Pixel viewer 47/Aug.
 Planar p-i-n diodes 50/Feb.
 Plug-ins, oscilloscope 11, 68/Oct.
 PMMA characteristics 68/Aug.
 Polarimeters 8/Feb.
 Polarization 55/Feb., 69/Dec.
 Polarization diversity receiver 42, 55/Feb.
 Polarization sensitivity 71/Dec.
 Polytope optimization 77/Apr.
 Portable Operating System Interface 41/June
 POSIX 41/June
 Power control, cellular 93/Dec.
 Power control, laser 29/Feb.

Power leveling 26/Apr.
 Power spectral density 64/Dec.
 Preamplifier 35/Dec.
 Preliminary hazard analysis 51/June
 Prestressing 36/Oct.
 Pretests 31/Apr.
 Pretrigger, oscilloscope 7/Oct.
 Priority inheritance 27, 29/Aug.
 Priority inversion 28/Aug.
 Privileges, HP OpenODB 29/June
 Probe, active 31/Oct.
 Probe fixture, wafer test 73/Oct.
 Process, HP-RT 27/Aug.
 Process scheduling, HP-RT 30/Aug.
 Program activity measurements 109/Apr.
 Protocol, DECT 98/Dec.
 Pulse/data channel 56/Apr.
 Pulse formatter 65/Apr.
 Pulse height accuracy 49/Oct.
 Pulse generator 27, 52/Apr.
 Pulse modulation 25/Apr.
 Pulse parameter accuracy 47/Oct.
 Pulse width accuracy 48/Oct.
 Pulse width generation 64/Apr.

Q

Quantizing error 107/Oct.
 Quantum efficiency 11/Aug.
 Quantum wells 7/Feb.

R

RAKE receiver 92/Dec.
 RAMDACs 36/June
 Real-time operating systems 23, 31/Aug.
 Real-time systems 23, 31, 90/Aug.
 Receiver design, HP 4396A 81, 85/Oct.
 Receivers, lightwave 83/Feb.
 Reconstruction, waveform 45/Oct.
 Reentrancy 25/Aug.
 Reference loop 16/Apr.
 Referential integrity 20/June
 Reflectometry 8, 39, 60/Feb.
 Register allocation, logic synthesis 46/Aug.
 Reliability, industrial workstation 64/Aug.
 Remote access 15/Aug.
 Remote debugging 29/Dec.
 Resampling 10/Dec.
 Residual interpolator 28/Oct.
 Resolution bandwidth 79/Oct.
 Retroreflector 41/Feb.

Return loss measurement, HP 8146A 78/Feb.
 Return loss measurement, optical 79/Feb.
 Reverse link encoding 95/Dec.
 RF shield design 82/Oct.
 RF source 54/Dec.
 RF vector analyzer 47/Dec.
 RFI suppression 33/Dec.
 Rise time accuracy 47/Oct.
 RMON MIB 82/Apr.
 Robot system 6/June
 RTOS measurement tool 97/Apr.
 Rules 80/Aug.
 Run-time-configurable hardware drivers 20/Dec.

S

SAFD microcircuit 47/Apr.
 Sample rate, oscilloscope 14, 21/Oct.
 Sample-and-filter technique 16/Oct.
 Sampler chip 14, 17/Oct.
 Sampler, microwave 15/Apr.
 Sampling, electrooptic 9/Feb.
 Scale fidelity 78/Oct.
 Scaling, fixed-point 79/Apr.
 Scallop error 91/Oct.
 Scanner, color desktop 52/Aug.
 Scroll bars, sticky 102/Apr.
 Self-calibration 44/Apr.
 Self-test 43/Apr.
 Semaphores 28/Aug.
 Sensitivity tests, DECT 104/Dec.
 Separator, color 55/Aug.
 Serviceability, industrial workstation 63/Aug.
 Setjmp and longjmp 37/Aug.
 Shadow registers 34/Aug.
 Shaft encoder 78/Dec.
 Shared data structures 33/Aug.
 Short codes 94/Dec.
 Side-mode filter 13, 21/Feb.
 Side mode suppression ratio 67/Dec.
 Signal averaging 44, 63/Feb.
 Signal generators 6/Apr.
 Signal processing, HP 8504A 43/Feb.
 Signal-to-noise ratio 54, 63/Feb.
 Simulation, logic synthesis system 44/Aug.
 Simultaneous RF/baseband measurements 14/Dec.
 SNMP 82/Apr.
 Soft handoff 92/Dec.

SoftBench 93/Apr.
 Software defect management 73/Aug.
 Software, DSP 79/Apr.
 Software hazards 47/June
 Software inspections 60/June
 Software localization 64/June
 Sound intensity 74/Apr.
 Sound pressure 75/Apr.
 Source,
 vector signal analyzer 43, 54/Dec.
 Sources, tunable laser 11/Febr.
 Spatial diversity 92/Dec.
 Spatial resolution 54/Febr.
 Spectral power distribution 52/Aug.
 Spectral reflectance 52/Aug.
 Spectrum analyzer 76/Oct.
 Spectrum analyzer
 DECT measurements 98/Dec.
 Spectrum resolution 90/Oct.
 Speech encoding, cellular 93/Dec.
 Spontaneous emission, LEDs 63/Dec.
 Standard data format 85/Dec.
 Standard observers,
 CIE and NTSC 53/Aug.
 State machines 23/Dec.
 Statistics 111/Apr.
 Stimulated emission,
 Fabry-Perot lasers 65/Dec.
 Stitching, HP 8146A 64/Febr.
 Storage, oscilloscope 7/Oct.
 Stored function 26/June
 Stored procedures 80/Aug.
 Strain gauge amplifier 83/Dec.
 Strain gauges 83/Dec.
 Structured analysis
 and structured design 90/Aug.
 Subscription, message 96/Apr.
 Super VGA 31/June
 Surgical laser control 68/Aug.
 Surrogate object 24/June
 SVGA 31/June
 Switches, p-i-n 23/Apr.
 Sweepers, microwave 38/Apr.
 Synthesized signal generators 6/Apr.

System administration
 manager (SAM) 80/June
 System start 95/Apr.

T

Task Broker 15/Aug.
 Task structuring 92/Aug.
 Taumel etalon 23/Febr.
 Teach pendant, robot 12/June
 Temperature calibration 70/Apr.
 Temperature stabilization, laser 28/Febr.
 Templates 88/Aug.
 Test library management system
 (TLMS) 53/June
 Test set, optical return loss 82/Febr.
 Test suite hierarchy 55/June
 Threads 27/Aug.
 Time base, oscilloscope 24/Oct.
 Time diversity 92/Dec.
 Time-domain corrections 10/Dec.
 Time gated measurement 92/Oct.
 Time selective
 frequency analysis 15/Dec.
 Timeshare 31/Aug.
 Timing board, pulse generator 60/Apr.
 Topology graphs 40, 44/Aug.
 TQC 64/June
 Tramp errors 71/June
 Transaction error handling 72/June
 Transceiver, DECT 100/Dec.
 Transimpedance amplifier,
 HP 8504A 42/Febr.
 Transimpedance amplifier,
 HP 71450A/51A 71/Dec.
 Traveling-wave amplifier 22/Apr.
 Trigger system 24/Oct.
 Trigger, vector analyzer 45/Dec.
 Triggers 80/Aug.
 Tsutsuji system 38/Aug.
 Tunable laser sources 11/Febr.
 Two-axis micropositioner 80/Dec.
 Two-step decimation 90/Oct.
 Type, HP OpenODB 25/June

U

Ultrasound transducer analysis 13/Dec.
 Uncertainty, return loss 80/Feb.
 User interface 47, 72/Febr.
 User interface, HP 71450A/51A 61/Dec.
 User interface management system
 (UIMS) 80/June

V

Vector signal analyzers 6/Dec.
 VGA 31/June
 Video Graphics Array 31/June
 Video image procedures,
 assembly and test 35/Apr.
 Video RAM 34/June
 Virtual instruments 46/Aug.
 VMEbus 23, 33, 64/Aug.
 Vocoder 93/Dec.
 VRAM 34/June

W

Wafer test, amplifier 68/Apr.
 Wafer test fixture 73/Oct.
 Walsh codes 93/Dec.
 Water vapor absorption 58/Febr.
 Wavelength calibration, laser 25/Febr.
 Wavelength sweep 18/Febr.
 WDM 11/Febr.
 White-light interferometry 39/Febr.
 Width board, pulse generator 64/Apr.
 Windows display driver 39/June
 Windows, synchronous 101/Apr.
 Work groups, HP Task Broker 20/Aug.
 Worm drive 77/Dec.

XYZ

YIG oscillator 51/Dec.
 YIG oscillators 12, 46/Apr.
 Zero-span measurements 12/Dec.
 Zeroing and chopping,
 HP 71450A/51A 73/Dec.
 Zoom filtering 102/Oct.

Part 3: Product Index

HP 3569A Portable Real-Time Frequency Analyzer	Apr.	HP 83712A Synthesized Signal Generator	Apr.
HP 4396A 1.8-GHz Vector Network and Spectrum Analyzer ..	Oct.	HP 83731A Synthesized Signal Generator	Apr.
HP 8133A 3-GHz Pulse Generator	Apr.	HP 83732A Synthesized Signal Generator	Apr.
HP 8146A Optical Time-Domain Reflectometer	Feb.	HP 83750 Series Microwave Sweepers	Apr.
HP 8153A Lightwave Multimeter	Feb.	HP 83751A Microwave Sweeper	Apr.
HP 8167A Tunable Laser Source	Feb.	HP 83751B Microwave Sweeper	Apr.
HP 8168A Tunable Laser Source	Feb.	HP 83752A Microwave Sweeper	Apr.
HP 8370 Series Signal Generators and Sweepers	Apr.	HP 83752B Microwave Sweeper	Apr.
HP 8504A Precision Reflectometer	Feb.	HP 85723A DECT Measurement Personality	Dec.
HP 8590 E-Series Spectrum Analyzers	Dec.	HP 89410A Vector Signal Analyzer	Dec.
HP 54701A Active Probe	Oct.	HP 89411A 1.8-GHz Down-Converter	Dec.
HP 54710A/D Oscilloscope	Oct.	HP 89440A RF Section	Dec.
HP 54711A Attenuator Plug-in	Oct.	HP 89440A Vector Signal Analyzer	Dec.
HP 54712A Amplifier Plug-in	Oct.	HP 9000 Model 742rt Computer	Aug.
HP 54713A Amplifier Plug-in	Oct.	HP E1430A ADC module	Oct.
HP 54714A Amplifier Plug-in	Oct.	HP HLMA-BL00, CL00, DL00, KL00, CH00, DH00, KH00, DG00 Light-Emitting Diodes	Aug.
HP 54720A/D Oscilloscope	Oct.	HP Lan Probe II RMON MIB Network Monitor	Apr.
HP 54721A Amplifier Plug-in	Oct.	HP OpenODB	June
HP 54722A Attenuator Plug-in	Oct.	HP ORCA Robot System	June
HP 64700 Embedded Debug Environment	Apr.	HP-RT Operating System	Aug.
HP 70340A Synthesized Signal Generator	Apr.	HP ScanJet IIc Scanner	Aug.
HP 70341A Synthesized Signal Generator	Apr.	HP Task Broker	Aug.
HP 71450A and 71451A Optical Spectrum Analyzers	Dec.	HP Tsutsuji Logic Synthesis System	Aug.
HP 81534A Return Loss Module	Feb.	HP Ultra VGA	June
HP 83440 Series Lightwave Detectors	Feb.	MPE/iX Operating System	June
HP 83711A Synthesized Signal Generator	Apr.		

Part 4: Author Index

Adams, Nancy	June	Booster, D. Howard	Feb.	Cristal, Edward G.	Apr.
Ahad, Rafiul	June	Bostak, Christopher J.	Apr.	Culbertson, W. Bruce	Aug.
Anzinger, George A.	Aug.	Braun, David M.	Feb.	Cutler, Robert T.	Dec.
Armstrong, Allan R.	Apr.	Brenneman, John S.	Apr.	D'Alessandro, John	Apr.
Assini, Renato G.	Aug.	Burdick, Matthew J.	Apr.	Deng, Yong	June
Azary, Zoltan	Dec.	Byrne, Patrick J.	Oct.	Diederichs, Joseph R.	Dec.
Bailey, David A.	Dec.	Campbell, John W.	Oct.	Dippon, Thomas	Apr.
Bartz, Manfred	Dec.	Canestri, Franco A.	Aug.	Dotseth, Mike	Apr.
Baumgartner, William D.	Apr.	Carey, Kent W.	Feb.	Duff, Christopher P.	Oct.
Bayern, Keith A.	Dec.	Chang, Kok Wai	Feb.	Elo, Mark A.	Dec.
Beck, Patricia A.	Feb.	Chau, Samuel H.	June	Engel, Glenn R.	Dec.
Beller, Josef	Feb.	Cheng, Tu-Ting	June	Escovitz, William H.	Oct.
Berger, Arnold S.	Apr.	Chodora, Jason A.	Apr.	Eskeldson, David D.	Oct.
Blasciak, Andrew J.	Apr.	Chou, Harry	Feb.	Ferguson, Thomas C.	Apr.
Bloom, Alan R.	Apr.	Clements, Brad	Aug.	Fischer, Thomas	Apr.
Blue, Kenneth J.	Dec.	Connolly, Brian	June	Fisher, Peter H.	Apr.

Fletcher, Robert M.	Aug.	Leckel, Edgar	Feb.
Gennetten, K. Douglas	Aug.	Lewis, John M.	Aug.
Ginder, William J.	Dec.	Long, David W.	Oct.
Goodnow, John W.	June	Luszcz, Joseph M.	Aug.
Gordon, Gary B.	June	MacLeod, Jean M.	June
Graeber, Roger R.	Apr.	Madden, Christopher J.	Feb.
Graf, Terrence P.	Aug.	Magnuson, Christopher J.	Oct.
Grisell, Thomas L.	Apr.	Maier, Daniel G.	Aug.
Gronlund, Robert D.	Apr.	Maier, Frank	Feb.
Hall, Michael L.	Dec.	Maisenbacher, Bernd	Feb.
Hamling, Daniel T.	Oct.	Mason, Roy L.	Dec.
Hammond, Cindie A.	June	McQuate, David J.	Feb.
Hart, Michael G.	Feb.	McTigue, Michael T.	Oct.
Heinz, William W.	Apr.	Mifsud, Steven J.	Feb.
Helgoth, Wayne F.	Oct.	Montijo, Allen	Oct.
Heyman, Eric V.V.	Apr.	Morgan, Kevin D.	Aug.
Hiller, Don	Dec.	Müller, Emmerich	Feb.
Hillstrom, Timothy L.	Dec.	Neuder, David L.	Apr.
Hilton, Howard E.	Oct.	Newton, Steven A.	Feb.
Hinch, Stephen W.	Feb.	Notess, Mark H.	June
Hoffmann, Brian E.	Aug.	Nukiyama, Akira	Oct.
Howell, Douglas K.	Aug.	Nygaard, Richard A., Jr.	Apr.
Imperato, John L.	Apr.	O'Brien, Dennis P.	Dec.
Ishak, Waguil S.	Feb.	O'Konski, Timothy C.	Aug.
Jahn, Robert	Feb.	Osame, Toshiki	Aug.
James, Rick R.	Apr.	Osentowski, Timothy D.	Aug.
Johnson, Dana L.	Oct.	Otsuru, Yoshisuke	Aug.
Johnson, Kenneth W.	Oct.	Peregrino, Ricardo de Mello	Apr.
Johnson, Kevin L.	Dec.	Pfaff, Andreas	Apr.
Jungerman, Roger L.	Feb.	Pietsch, James	Dec.
Kalkuhl, Christoph	Apr.	Pless, Wilfried	Feb.
Kawabata, Shigeru	Oct.	Pott, Michael	Feb.
Keefer, David A.	Aug.	Pratt, Ronald E.	Apr.
Kellum, Reginald	Oct.	Rafnel, Bruce A.	June
Kelley, David F.	Dec.	Rasper, John T.	Apr.
King, Randall	Feb.	Rawson, Rollin F.	Feb.
Knight, J. Douglas	Dec.	Reichert, Wolfgang	Feb.
Kolseth, Camala S.	Apr.	Roark, Joseph C.	June
Koppes, William A.	June	Robbins, Virginia M.	Aug.
Krieger, John J.	June	Rom, George	June
Kuo, Chihping	Aug.	Rovell-Rixx, D. Kris	June
Lalwani, Rajesh	June	Rück, Clemens	Feb.
Larson, Douglas A.	Apr.	Rush, Kenneth	Oct.
		Salomaa, Kari K.	Feb.
		Scharrer, John A.	Oct.
		Schinzel, Peter	Apr.
		Schlater, Rodney T.	Oct.
		Schleifer, Arthur	June
		Schmidt, Siegmar	Feb.
		Schroath, Leonard T.	June
		Schweikardt, Horst	Feb.
		Seeger, Harald	Feb.
		Shackleford, J. Barry	Aug.
		Sharpe, Edward J.	Aug.
		Short, Brian R.	Apr.
		Shubert, Karl	Feb.
		Sloan, Susan	Feb.
		Smith, Kevin G.	Apr.
		Sorin, Wayne V.	Feb.
		Steiner, Rolf	Feb.
		Steinle, Michael J.	Aug.
		Sternier, John R.	Oct.
		Stimple, James R.	Dec.
		Tanaka, Motoo	Aug.
		Tarantino, Joe	Dec.
		Taylor, Gregory A.	Apr.
		Trutna, William R., Jr.	Feb.
		Turner, James J.	Aug.
		Tuttle, Myron R.	June
		Uhling, Thomas F.	Oct.
		Wagner, Douglas R.	Dec.
		Wagner, Hans-Jürgen	Apr.
		Waite, James W.	Apr.
		Ward, Michael C.	Aug.
		Warner, Sandra J.	June
		West, Joseph N.	Dec.
		Whipple, David P.	Dec.
		Whiteman, Donald A.	Oct.
		Wildnauer, Kenneth R.	Dec.
		Wilson, Kenneth M.	June
		Yanagimoto, Yoshiyuki	Oct.
		Yu, Jiann Gwo	Aug.
		Zellers, James R.	Apr.
		Zorabedian, Paul	Feb.
		Zarlingo, Benjamin R.	Dec.